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Keypad Decoder and I/O Expansion

Data Sheet **ADP5585**

FEATURES

16-element FIFO for event recording 10 configurable I/Os allowing functions such as Key pad decoding for a matrix of up to 5 × 5 11 GPIOs (5 × 6) with ADP5585ACxZ-01-R7 models Key press/release interrupts GPIO functions GPI with selectable interrupt level 100 kΩ or 300 kΩ pull-up resistors 300 kΩ pull-down resistors GPO with push-pull or open-drain Programmable logic block PWM generator Internal PWM generation External PWM with internal PWM AND function Reset generators I ²C interface with fast mode plus (Fm+) support of up to 1 MHz Open-drain interrupt output 16-ball WLCSP, 1.59 mm × 1.59 mm 16-lead LFCSP, 3 mm × 3 mm

APPLICATIONS

Keypad entries and input/output expansion capabilities Smart phones, remote controls, and cameras Healthcare, industrial, and instrumentation

GENERAL DESCRIPTION

The ADP5585 is a 10 input/output port expander with a built in keypad matrix decoder, programmable logic, reset generator, and PWM generator. Input/output expander ICs are used in portable devices (phones, remote controls, and cameras) and nonportable applications (healthcare, industrial, and instrumentation). I/O expanders can be used to increase the number of I/Os available to a processor or to reduce the number of I/Os required through interface connectors for front panel designs.

The ADP5585 handles all key scanning and decoding and can flag the main processor via an interrupt line that new key events have occurred. GPI changes and logic changes can also be tracked

as events via the FIFO, eliminating the need to monitor different registers for event changes. The ADP5585 is equipped with a FIFO to store up to 16 events. Events can be read back by the processor via an I²C-compatible interface.

The ADP5585 frees up the main processor from having to monitor the keypad, thereby reducing power consumption and/or increasing processor bandwidth for performing other functions.

The programmable logic functions allow common logic requirements to be integrated as part of the GPIO expander, thus saving board area and cost.

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REVISION HISTORY

$7/12$ -Rev. A to Rev B

10/11-Rev. Sp0 to Rev. A

5/11-Revision Sp0: Initial Version

SPECIFICATIONS

VDD = 1.8 V to 3.3 V, $T_A = T_J = -40\degree C$ to +85 $\degree C$, unless otherwise noted¹.

Table 1.

 1 All limits at temperature extremes are guaranteed via correlation using standard statistical quality control (SQC). Typical values are at T $_A$ = 25°C, VDD = 1.8 V.

² Guaranteed by design.

3 All timers are referenced from the base oscillator and have the same ±10% accuracy.

 4 C_B is the total capacitance of one bus line in picofarads.

TIMING DIAGRAM

Figure 2. I2C Interface Timing Diagram

ABSOLUTE MAXIMUM RATINGS

Table 2.

¹ In applications where high power dissipation and poor thermal resistance are present, the maximum ambient temperature may need to be derated. Maximum ambient temperature $(T_{A \, (MAX)})$ is dependent on the maximum operating junction temperature ($T_{J (MAXOP)} = 125$ °C), the maximum power dissipation of the device ($P_{D (MAX)}$), and the junction-to-ambient thermal resistance of the device/package in the application (θ_{JA}) , using the following equation: $T_{A (MAX)} = T_{J (MAXOP)} - (\theta_{JA} \times P_{D (MAX)}).$

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Absolute maximum ratings apply individually only, not in combination. Unless otherwise specified, all other voltages are referenced to GND.

THERMAL RESISTANCE

 $\theta_{\rm JA}$ is specified for the worst-case conditions, that is, a device soldered in a printed circuit board (PCB) for surface-mount packages.

Table 3.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

Table 4. Pin Function Descriptions

THEORY OF OPERATION **VDD GND ADP5585 UVLO RST/R5 OSCILLATOR POR SDA** γ int **I 2C INTERFACE SCL I 2C BUSY? R0 KEY EVENT FIFO UPDATE GPI EVENT (R0) (R1) ROW 0 ROW 1 ROW 2 ROW 3 ROW 4 ROW 5 R1** ₹
C **LOGIC EVENT (R2) (R3) R2 (R4) (RST/R5) KEY SCAN AND DECODE (C0) R3** ş **COL 1 COL 0 (C1) (C2) COL 2 COL 3 R4** Ċ **(C3) (C4)** $\frac{COL3}{COL4}$ **C0 (R0) (R1) (R2) (R3) GPIO 1 GPIO 2 GPIO 3 GPIO 4 GPIO 5 REGISTERS C1 GPI SCAN (R4) (RST/R5) C2 GPIO 6 GPIO 7 GPIO 8 GPIO 9 GPIO 10 AND DECODE (C0) (C1) (C2) C3 (C3) (C4) I/O CONFIGURATION GPIO 11 C4 (R1) (R2) LA LB LOGIC (R3) LC (R0) LY (C3) PWM_IN (R3) PWM PWM_OUT** $\left\{ \begin{array}{c} \overline{\overline{z}} \\ \overline{\overline{z}} \end{array} \right\}$ **(R4) RESET1 RESET1 GEN RST (R5) RESET2 (C4) RESET2 GEN** 09841-004

Figure 5. Internal Block Diagram

DEVICE ENABLE

When sufficient voltage is applied to VDD and the $\overline{\text{RST}}$ pin is driven with a logic high level, the ADP5585 starts up in standby mode with all settings at default. The user can configure the device via the I²C interface. When the $\overline{\text{RST}}$ pin is low, the ADP5585 enters a reset state and all settings return to default. The RST pin features a debounce filter.

If using the ADP5585ACBZ-01-R7 or ADP5585ACPZ-01-R7 device model, the RST pin acts as an extra row pin. Without a reset pin, the only method to reset the device is by bringing VDD below the UVLO threshold.

DEVICE OVERVIEW

The ADP5585 contains 10 multiconfigurable input/output pins. Each pin can be programmed to enable the device to carry out its various functions, as follows:

- Keypad matrix decoding (five-column by five-row matrix maximum).
- General-purpose I/O expansion (up to 10 inputs/outputs).
- PWM generation.
- Logic function building blocks (up to three inputs and one output).
- Two reset generators.

All 10 input/output pins have an I/O structure as shown in Figure 6.

Each I/O can be pulled up with a 100 k Ω or 300 k Ω resistor or pulled down with a 300 k Ω resistor. For logic output drive, each I/O has a 5 mA PMOS source and a 10 mA NMOS sink for a pushpull type output. For open-drain output situations, the 5 mA PMOS source is not enabled. For logic input applications, each I/O can be sampled directly or, alternatively, sampled through a debounce filter.

The I/O structure shown in Figure 6 allows for all GPI and GPO functions, as well as PWM and clock divide functions. For key matrix scan and decode, the scanning circuit uses the 100 k Ω or 300 k Ω resistor for pulling up keypad row pins and the 10 mA NMOS sinks for grounding keypad column pins (see the Key Scan Control section for details about key decoding).

Configuration of the device is carried out by programming an array of internal registers via the I ²C interface. Feedback of device status and pending interrupts can be flagged to an external processor by using the \overline{INT} pin.

The ADP5585 is offered with three feature sets. Table 5 lists the options that are available for each model of the ADP5585.

Table 5. Matrix Options by Device Model

¹ Special function pins are defined as R0, R3, R4, and C4. See Table 4 for details.

FUNCTIONAL DESCRIPTION **EVENT FIFO**

Before going into detail on the various ADP5585 blocks, it is important to understand the function of the event FIFO. The ADP5585 features an event FIFO that can record as many as 16 events. By default, the FIFO primarily records key events, such as key press and key release. However, it is possible to configure the general-purpose input (GPI) and logic activity to generate event information on the FIFO as well. An event count, EC[4:0], is composed of five bits and works in tandem with the FIFO so that the user knows how much of the FIFO must be read back at any given time.

The FIFO is composed of 16 eight-bit sections that the user accesses by reading the FIFO_x registers. The actual FIFO is not in user accessible registers until a read occurs. The FIFO can be thought of as a "first in first out" buffer that is used to fill Register 0x03 to Register 0x12.

The event FIFO is made up of 16 eight-bit registers. In each register, Bits[6:0] hold the event identifier, and Bit 7 holds the event state. With seven bits, 127 different events can be identified. See Table 11 for event decoding.

Figure 7. Breakdown of Eventx[7:0] Bits

When events are available on the FIFO, the user should first read back the event count, EC[4:0], to determine how many events must be read back. Events can be read from the top of the FIFO only. When an event is read back, all remaining events in the FIFO are shifted up one location, and the EC[4:0] count is decremented.

Figure 8. FIFO Operation

The FIFO registers (0x03 to 0x12) always point to the top of the FIFO (that is, the location of EVENT1[7:0]). If the user tries to read back from any location in a FIFO, data is always obtained from the top of that FIFO. This ensures that events can only be read back in the order in which they occurred, thus ensuring the integrity of the FIFO system.

As stated above, some of the onboard functions of ADP5585 can be programmed to generate events on the FIFO. A FIFO update control block manages updates to the FIFO. If an I²C transaction is accessing any of the FIFO address locations, updates are paused until the I²C transaction has completed.

A FIFO overflow event occurs when more than 16 events are generated prior to an external processor reading a FIFO and clearing it.

If an overflow condition occurs, the overflow status bit is set. An interrupt is generated if overflow interrupt is enabled, signaling to the processor that more than 16 events have occurred.

KEY SCAN CONTROL

General

The 10 input/output pins can be configured to decode a keypad matrix up to a maximum size of 25 switches (5×5 matrix). Smaller matrices can also be configured, freeing up the unused row and column pins for other I/O functions.

The R0 through R4 I/O pins comprise the rows of the keypad matrix. The C0 through C4 I/O pins comprise the columns of the keypad matrix. Pins used as rows are pulled up via the internal 300 k Ω (or 100 k Ω) resistors. Pins used as columns are driven low via the internal NMOS current sink.

┎

09841-008

VDD

KEY SCAN CONTROL

 \overline{t}

Figure 9 shows a simplified representation of the key scan block using three row and three column pins connected to a small 3×3 , nine-switch keypad matrix. When the key scanner is idle, the row pins are pulled high and the column pins are driven low. The key scanner operates by checking the row pins to see if they are low.

If Switch 6 in the matrix is pressed, R1 connects to C2. The key scan circuit senses that one of the row pins has been pulled low, and a key scan cycle begins. Key scanning involves driving all column pins high, then driving each column pin, one at a time,

low and sensing whether a row pin is low or not. All row/column pairs are scanned; therefore, if multiple keys are pressed, they

To prevent glitches or narrow press times being registered as a valid key press, the key scanner requires the key be pressed for two scan cycles. The key scanner has a wait time between each scan cycle; therefore, the key must be pressed and held for at least this wait time to register as being pressed. If the key is continuously pressed, the key scanner continues to scan, wait, scan, wait, and so forth.

If Switch 6 is released, the connection between R1 and C2 breaks, and R1 is pulled up high. The key scanner requires that the key be released for two scan cycles because the release of a key is not necessarily in sync with the key scanner, it may take up to two full wait/scan cycles for a key to register as released. When the key is registered as released, and no other keys are pressed, the key scanner returns to idle mode.

For the remainder of this document, the press/release status of a key is represented as simply a logic signal in the figures. A logic high level represents the key status as pressed, and a logic low represents released. This eliminates the need to draw individual row/column signals when describing key events.

Figure 11 shows a detailed representation of the key scan block and its associated control and status signals. When all row and column pins are used, a matrix of 25 unique keys can be scanned.

Data Sheet **ADP5585**

Use Registers PIN_CONFIG_A[7:0] and PIN_CONFIG_B[7:0] to configure I/Os for keypad decoding. The number label on each key switch represents the event identifier that is recorded if that switch was pressed. If all row/column pins are configured, it is possible to observe all 25 key identifiers on the FIFO. A larger 6×5 matrix can be configured by using the ADP5585ACBZ-01-R7 or the ADP5585ACPZ-01-R7.

If a smaller 2×2 matrix is configured, for example, by using the C2 and C3 column pins and the R1 and R2 row pins, only the four event identifiers (8, 9, 13, and 14) can possibly be observed on the FIFO, as shown in Figure 11.

By default, ADP5585 records key presses and releases on the FIFO. Figure 12 illustrates what happens when a single key is pressed and released. Initially, the key scanner is idle. When Key 3 is pressed, the scanner begins scanning through all configured row/column pairs. After the scan wait time, the scanner again scans through all configured row/column pairs and detects that Key 3 has remained pressed, which sets the EVENT_INT interrupt. The event counter, EC[4:0], is incremented to 1, EVENT1_IDENTIFIER[6:0] of the FIFO is updated with its event identifier set to 3, and its EVENT1_STATE bit is set to 1, indicating a press.

The key scanner continues the scan/wait cycles while the key remains pressed. If the scanner detects that the key has been released for two consecutive scan cycles, the event counter, EC[4:0], is incremented to 2, and EVENT2_IDENTIFIER[6:0] of the FIFO is updated with its event identifier set to 3. Its EVENT2_STATE bit is set to 0, indicating a release. The key scanner returns to idle mode because no other keys are pressed.

The EVENT_INT interrupt can be triggered by both press and release key events. As shown in Figure 14, if Key 3 is pressed, EVENT_INT is asserted, EC[4:0] is updated, and the FIFO is updated. During the time that the key remains pressed, it is possible for the FIFO to be read, the event counter decremented to 0, and EVENT_INT cleared. When the key is finally released, EVENT INT is asserted, the event counter is incremented, and the FIFO is updated with the release event information.

Figure 13. Asserting the EVENT_INT Interrupt Key Pad Extension

As shown in Figure 11, the keypad can be extended if each row is connected directly to ground by a switch. If the switch placed between R0 and ground is pressed, the entire row is grounded. When the key scanner completes scanning, it normally detects Key 1 to Key 5 as being pressed; however, this unique condition is decoded by the ADP5585, and Key Event 31 is assigned to it. Up to eight more key event assignments are possible, allowing the keypad size to extend up to 30. However, if one of the extended keys is pressed, none of the keys on that row is detectable. Activation of a ground key causes all other keys sharing that row to be undetectable.

Ghosting

Ghosting is an occurrence where, given certain key press combinations on a keypad matrix, a false positive reading of an additional key is detected. Ghosting is created when three or more keys are pressed simultaneously on multiple rows or columns (see Figure 14). Key combinations that form a right angle on the keypad matrix can cause ghosting.

The solution to ghosting is to select a keypad matrix layout that takes into account three key combinations that are most likely to be pressed together. Multiple keys pressed across one row or across one column do not cause ghosting. Staggering keys so that they do not share a column also avoids ghosting. The most common practice is to place keys that are likely to be pressed together in the same row or column. Some examples of keys that are likely to be pressed together are as follows:

- The navigation keys in combination with Select.
- The navigation keys in combination with the space bar.
- The reset combination keys, such as CTRL + ALT + DEL.

Figure 14. COL0: ROW3 is a Ghost Key Due to a Short Among ROW0, COL0, COL2, and ROW3 During Key Press

GPI INPUT

Each of the 10 input/output lines can be configured as a general-purpose logic input line. Figure 15 shows a detailed representation of the GPI scan and detect block and its associated control and status signals.

Figure 15. GPI Scan and Detect Block

The current input state of each GPI can be read back using the GPI_STATUS_x registers. Each GPI can be programmed to generate an interrupt via the GPI_INTERRUPT_EN_x registers. The interrupt status is stored in the GPI_INT_STAT_x registers. GPI interrupts can be programmed to trigger on the positive or negative edge by configuring the GPI_INT_LEVEL_x registers. If any of the GPI interrupts is triggered, the master GPI_INT interrupt is also triggered. Figure 16 shows a single GPI and how it affects its corresponding status and interrupt status bits.

GPIs can be programmed to generate FIFO events via the GPI_EVENT_EN_x registers. GPIs in this mode do not generate GPI_INT interrupts and instead generate EVENT_INT interrupts. Figure 17 shows several GPI lines and their effects on the FIFO and event count, EC[4:0].

The GPI scanner is idle until it detects a level transition. It scans the GPI inputs and updates accordingly. It then returns to idle immediately, it does not scan/wait, like the key scanner. As such, the GPI scanner can detect narrow pulses once they get past the 50 μs input debounce filter.

GPO OUTPUT

Each of the 10 input/output lines can be configured as a generalpurpose output (GPO) line. Figure 6 shows a detailed diagram of the I/O structure. See the Detailed Register Descriptions section for GPO configuration and usage.

LOGIC BLOCKS

Several of the ADP5585 input/output lines can be used as inputs and outputs for implementing some common logic functions.

The R1, R2, and R3 input/output pins can be used as inputs, and the R0 input/output pin can be used as an output for the logic block.

The outputs from the logic blocks can be configured to generate interrupts. They can also be configured to generate events on the FIFO.

Figure 19 shows a detailed diagram of the internal make-up of the logic block, illustrating the possible logic functions that can be implemented.

Data Sheet **ADP5585**

(C3) PWM_IN

PWM_ONT_HIGH_BYTE[7:0] ON TIME[15:0]

PWM_ONT_LOW_BYTE[7:0]

PWM_IN_AND

The ADP5585 features a PWM generator whose output can be configured to drive out on the R3 I/O pin. PWM on/off times are programmed via four 8-bit registers (see Figure 20). Each bit of the on or off time represents 1 µs. The highest frequency obtainable from the PWM is performed by setting the least significant bit of both the on and off time bit patterns, resulting in a 500 kHz signal with a 50% duty cycle.

The PWM block provides support for continuous PWM mode as well as a one-shot mode (see Table 59). Additionally, an external signal can be AND'ed with the internal PWM signal. This option can be selected by writing a 1 to PWM_IN_AND (PWM_CFG[2]). The input to the external AND is the C3 I/O pin. C3 should be set to GPI. Note that the debounce for C3 results in a delay of the AND'ing, and can be turned on or off

Newly programmed values are not latched until the final byte, PWM_ONT_HIGH_BYTE (Register 0x32, Bits[7:0]), is written.

LY

LY

OUT ⁰ 1

(R3) PWM_OUT

AND

09841-018

LY_INV SEL OUT 0 1

09841-019

LY

PWM GENERATOR

RESET BLOCKS

ADP5585 features two reset blocks that can generate reset conditions if certain events are detected simultaneously. Up to three reset trigger events can be programmed for RESET1. Up to two reset trigger events can be programmed for RESET2. The event scan control blocks monitor whether these events are present for the duration of RESET_TRIG_TIME[2:0] (Register 0x2E, Bits[4:2]). If they are, reset-initiate signals are sent to the reset generator blocks. The generated reset signal pulse width is programmable.

The Reset 1 signal uses the R4 I/O pin as its output. A pass through mode allows the main $\overline{\text{RST}}$ pin to be output on the R4 pin also. The Reset 2 signal uses the C4 I/O pin as its output.

The reset generation signals are useful in situations where the system processor has locked up and the system is unresponsive to input events. The user can press one of the reset event combinations and initiate a system wide reset. This alleviates the need for removing the battery from the system and doing a hard reset.

It is not recommended to use the immediate trigger time (see Table 54) because this setting may cause false triggering.

Interrupts

The INT pin can be asserted low if any of the internal interrupt sources is active. The user can select which internal interrupts interact with the external interrupt pin in Register 0x3C (refer to Table 68). Register 0x3B allows the user to choose whether the external interrupt pin remains asserted, or deasserts for 50 µs, then reasserts, in the case that there are multiple internal interrupts asserted and one is cleared (refer to Table 67).

REGISTER INTERFACE

Register access to the ADP5585 is acquired via its I²C-compatible serial interface. The interface can support clock frequencies of up to 1 MHz. If the user is accessing the FIFO or key event counter (KEC), FIFO/KEC updates are paused. If the clock frequency is very low, events may not be recorded in a timely manner. FIFO or KEC updates can happen up to 23 µs after an interrupt is asserted because of the number of I²C cycles required to perform an I²C read or write. This delay should not present an issue to the user.

Figure 23 shows a typical write sequence for programming an internal register. The cycle begins with a start condition, followed by the hard coded 7-bit device address, which for the ADP5585 is 0x34, followed by the R/\overline{W} bit set to 0 for a write cycle. The ADP5585 acknowledges the address byte by pulling the data line low. The address of the register to which data is to be written is sent next. The ADP5585 acknowledges the register pointer byte by pulling the data line low. The data byte to be written is sent next. The ADP5585 acknowledges the data byte by pulling the data line low. A stop condition completes the sequence.

Figure 24 shows a typical multibyte write sequence for programming internal registers. The cycle begins with a start condition followed by the 7-bit device address (0x34 for all models except the ADP5585ACPZ-03-R7, 0x30 for the ADP5585ACPZ-03-R7 only), followed by the R/W bit set to 0 for a write cycle. The ADP5585 acknowledges the address byte by pulling the data

line low. The address of the register to which data is to be written is sent next. The ADP5585 acknowledges the register pointer byte by pulling the data line low. The data byte to be written is sent next. The ADP5585 acknowledges the data byte by pulling the data line low. The pointer address is then incremented to write the next data byte, until it finishes writing the n data byte. The ADP5585 pulls the data line low after every byte, and a stop condition completes the sequence.

Figure 25 shows a typical byte read sequence for reading internal registers. The cycle begins with a start condition followed by the 7-bit device address (0x34 for all models except the ADP5585ACPZ-03-R7, 0x30 for the ADP5585ACPZ-03-R7 only), followed by the R/\overline{W} bit set to 0 for a write cycle. The ADP5585 acknowledges the address byte by pulling the data line low. The address of the register from which data is to be read is sent next. The ADP5585 acknowledges the register pointer byte by pulling the data line low. A start condition is repeated, followed by the 7-bit device address (0x34 for all models except the ADP5585ACPZ-03-R7, 0x30 for the ADP5585ACPZ-03-R7 only), followed by the R/W bit set to 1 for a read cycle. The ADP5585 acknowledges the address byte by pulling the data line low. The 8-bit data is then read. The host pulls the data line high (no acknowledge), and a stop condition completes the sequence.

Figure 26 shows a typical multibyte read sequence for reading internal registers. The cycle begins with a start condition, followed by the 7-bit device address (0x34 for all models except the ADP5585ACPZ-03-R7, 0x30 for the ADP5585ACPZ-03-R7 only), followed by the R/\overline{W} bit set to 0 for a write cycle. The ADP5585 acknowledges the address byte by pulling the data line low. The address of the register from which data is to be read is sent next. The ADP5585 acknowledges the register pointer byte by pulling the data line low. A start condition is repeated, followed by the 7-bit device address (0x34 for all models except the

ADP5585ACPZ-03-R7, 0x30 for the ADP5585ACPZ-03-R7 only), followed by the R/\overline{W} bit set to 1 for a read cycle. The ADP5585 acknowledges the address byte by pulling the data line low. The 8-bit data is then read. The address pointer is then incremented to read the next data byte, and the host continues to pull the data line low for each byte (master acknowledge) until the n data byte is read. The host pulls the data line high (no acknowledge) after the last byte is read, and a stop condition completes the sequence.

REGISTER MAP

Table 6.

¹ R means read, W means write, and R/W means read/write.

DETAILED REGISTER DESCRIPTIONS

Note that N/A throughout this section means not applicable.

Note: All register default to 0000 0000 unless otherwise specified.

ID Register 0x00

Table 7. ID Bit Descriptions

INT_STATUS Register 0x01

Table 8. INT_STATUS Bit Descriptions

1 Interrupt bits are cleared by writing a 1 to the flag; writing a 0 or reading the flag has no effect.

Status Register 0x02

Table 9. Status Bit Descriptions

FIFO_1 Register 0x03

Table 10. FIFO_1 Bit Descriptions

FIFO_2 Register 0x04

Table 12. FIFO_2 Bit Descriptions

FIFO_3 Register 0x05

Table 13. FIFO_3 Bit Descriptions

FIFO_4 Register 0x06

Table 14. FIFO_4 Bit Descriptions

FIFO_5 Register 0x07

Table 15. FIFO_5 Bit Descriptions

FIFO_6 Register 0x08

Table 16. FIFO_6 Bit Descriptions

FIFO_7 Register 0x09

Table 17. FIFO_7 Bit Descriptions

FIFO_8 Register 0x0A

Table 18. FIFO_8 Bit Descriptions

FIFO_9 Register 0x0B

Table 19. FIFO_9 Bit Descriptions

FIFO_10 Register 0x0C

Table 20. FIFO_10 Bit Descriptions

FIFO_11 Register 0x0D

Table 21. FIFO_11 Bit Descriptions

FIFO_12 Register 0x0E

Table 22. FIFO_12 Bit Descriptions

FIFO_13 Register 0x0F

Table 23. FIFO_13 Bit Descriptions

FIFO_14 Register 0x10

Table 24. FIFO_14 Bit Descriptions

FIFO_15 Register 0x11

Table 25. FIFO_15 Bit Descriptions

FIFO_16 Register 0x12

Table 26. FIFO_16 Bit Descriptions

GPI_INT_STAT_A Register 0x13

Table 27. GPI_INT_STAT_A Bit Descriptions

GPI_INT_STAT_B Register 0x14

Table 28. GPI_INT_STAT_B Bit Descriptions

GPI_STATUS_A Register 0x15

Table 29. GPI_STATUS_A Bit Descriptions

GPI_STATUS_B Register 0x16

Table 30. Register 0x16, GPI_STATUS_B Bit Descriptions

RPULL_CONFIG_A Register 0x17

ADP5585ACBZ-02-R7 Default = 1100 0011

ADP5585ACBZ-04-R7 Default = 0101 0101

RPULL_CONFIG_B Register 0x18

Table 32. RPULL_CONFIG_B Bit Descriptions

ADP5585ACBZ-02-R7 Default = 0000 0011

ADP5585ACBZ-04-R7 Default = 0000 0101